## The Energetiq EQ-10 EUV source for metrology --**Review of recent data**

## ENERGETIQ

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## 6.7nm Electrodeless Z-Pinch Using Neon

EQ-10SXR Soft X-Ray Source Delivers Photons Reliably at 2.88nm: Modify for use at 6.7nm





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Drift due to camera motion (since corrected) Old algorithm – 22 microns  $(3\sigma)$ New algorithm – < 6 microns  $(3\sigma)$ 

Typical results from improved metrology -- < 3

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